

GPT-10000 Series

AC/DC/IR/GB Electrical Safety Analyzer

FEATURES

- DC 12 kV Output and 200 VA/500 VA AC Test Capacity (500 VA short circuit current>200 mA)
- 7" TFT LCD
- · Comply with IEC 61010-2-034 Design Requirement
- Manual Test Mode/Auto Test Mode
- RMS Current Measurement
- Zero Crossing Turn-on Operation
- · Controllable Ramp-up & Ramp-down Time
- · Statistics & Analysis Function
- Capacitive Load Testing Capability up to 47 μF
- . Sweep Function for DUT Characteristic Analysis
- Convenience Listed AUTO Mode Easy to Read Result and Judge
- Internal Storage and USB Storage Available
- Barcode Function Available
- Setting Data Export/Import
- Rear Panel Output Available
- Standard Interface: RS-232C, USB Host/Device and Signal I/O
- · Optional Interface: GPIB or LAN
- Universal Power Input





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GW Instek introduces the flagship model (high voltage DC 12 kV output and 500 VA/200 VA output capacity) safety analyzer-the GPT-10000 series, which is the first safety analyzer in the world to comply with IEC 61010-2-034 (Safety requirement for electrical requirement for measurement, control and laboratory use – particular requirements for measurement equipment for insulation resistance and test equipment for electric strength), which stipulates that the requirements of the software and hardware interfaces must be followed while designing high voltage and insulation resistance test and measurement instruments so as to ensure that users are provided with necessary protection and warning while using the instruments.

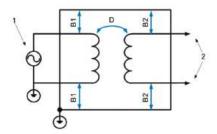
The GPT-10000 series safety analyzer has nine models: GPT-15012 supports DC withstanding test and insulation resistance test; GPT-15004 and GPT-12004 features AC/DC withstanding voltage test, insulation resistance test, AC ground bond test and continuity test; GPT-15003 and GPT-12003 conducts AC/DC withstanding voltage test, insulation resistance test, and continuity test; GPT-15002 and GPT-12002 carry out AC/DC withstanding voltage test and continuity test; GPT-15001 and GPT-12001 executes AC withstanding voltage test and continuity test. The entire series utilizes a high-efficient PWM amplifier to effectively exclude the influence from the fluctuating input voltage or distorted waveforms so as to guarantee a stable high-voltage output while conducting AC withstanding voltage test on the DUT to meet the safety regulations such as IEC, EN, UL, CSA, GB, JIS that demand the test requirements for various electronic/electrical products or parts.

To comply with IEC 61010-2-034 requirements, the series takes into account of safety by adopting the double insulation design for input power supply and output voltage to enhance user safety. Additionally, the retracted on-off switch design (START key) and various (optional) mechanisms for test activation (for instance, press and hold for 1 second to activate, activation by pressing double keys, etc.) are incorporated into the series to avoid accidentally touching that results in high voltage/large current output causing damage and danger to products or users. High illumination LED lights (flashing or permanently lit) and a high volume audial indicator are included in designing the series to provide warnings of the status of the on-going tests or judgement results from the safety analyzer. On top of that, the DUT will be automatically discharged to the safe voltage (approximately 30 V) after each test to prevent large residual test voltage from causing harm to users.

The series utilizes 7-inch color TFT LCD and inherits the consistent simplicity key design style of the product family to allow users to experience easy operations and a clear observation of the test results. Among the series, GPT-15012 supports high DC withstanding voltage test up to DC 12 kV, and the major test functions of other models include AC withstanding voltage test (AC 5 kV), DC withstanding voltage test (DC 6 kV), insulation resistance test (DC 50 V to 5000 V), ground bond test (AC 32 A), and grounding continuity test (DC 100 mA fixed). The series also collocates with superb output adjustment resolution, measurement resolution (AC withstanding voltage: 1 μ A; DC withstanding voltage: 0.1 μ A; insulation resistance: 0.1 M Ω ; ground bond: 0.1 M Ω ; continuity test: 0.01 Ω), controllable voltage ramp up and ramp down time settings, and upper/lower limit judgement settings, and large capacitance test capability (up to 47 μ F) for DUT with large capacitance such as surge absorber and large capacitance on the input terminal of EMC/EMI prevention. For Insulation resistance, provides 10 mA pre-charged current (fixed) to first rapidly fully charge the DUT's capacitive load and then to conduct test and measurement so as to avoid misjudgment from fluctuating inrush current. All the above features of the series facilitate a more flexible execution of the required tests so that users can obtain accurate test and measurement results.

The statistic function is the highlight of the series. Test items, number of tests, judgement results are recoded after testing and the test results can be shown by bar graph on the display. Users can immediately learn the status of product tests and judgement distribution during the manufacturing process without using a PC. The other strong feature is the sweep function, which can be used for the analysis on product's crash point. Users can use the sweep mode to see the curve diagram of the test results after finishing the functional tests. Users can also select any time point during the process to analyze the relation between voltage and current (when ACW or DCW is selected). The test result of the certain period of time can be swept by setting start and stop time points to analyze the relation between voltage and current under that time frame. Furthermore, the tabular continuity test function can combine 10 manual memory sets to carry out automatic tests or 9 manual memory sets with one connection device to connect next automatic test so as to increase the test items of the continuity test. Users can obtain various test values and judgement results without switching to a different display screen.

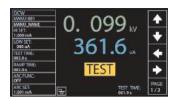
Other functions and features of the GPT-10000 series include 100 sets of manual test as well as 100 sets of auto test memory for the storage of different test conditions and the saved test conditions can be exported to another GPT-10000 through USB flash drive to quick replication and expansion of production line equipment; barcode scanner can be conducted to the front panel USB host of GPT-10000 for managing test condition of DUT and then be able to quick and correctly recall required test condition; rear output terminal for system integration; front panel remote control terminal mount/rear panel Signal I/O for users to conveniently control the analyzer's output/stop based upon the requirements. The USB storage function allows test results to be stored in the USB flash drive or internal memory to save the trouble of using a PC, and the function is conducive to the follow-up data analysis. For users with the requirements of PC control and test results recording, the series also provides RS-232C, USB and option GPIB or LAN.



Providing the markets with safe electronic products is the responsibility of every manufacturer! Similarly, safety analyzer that tests whether electronic products meet safety regulations must attach the importance to the safety it provides! GPT-10000 Series is the world's first safety analyzer to comply with IEC 61010-2-034 (Safety requirement for electrical requirement for measurement, control and laboratory use – particular requirements for

measurement equipment for insulation resistance and test equipment for electric strength). Apart from this, the safety considerations also include double insulation for input and output voltages, safe output/warning mechanism, post-test discharge mechanism, etc. to ensure user safety during the operation.

HIGH ACCURACY AND HIGH RESOLUTION TESTING PERFORMANCE

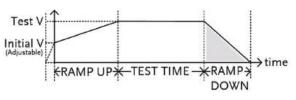


High Adjustment & Measurement Resolution

For production tests and characteristic verification, the GPT-10000 Series provides a withstand voltage test voltage (AC 5 kV/DC 6 kV) that can be adjusted in 1 V steps with current measurement resolutions up to 1 μA (ACW) or 0.1 μA (DCW) to realize the small leakage current measurement for products or components. In addition, the insulation resistance test voltage can be adjusted in 50 V steps from a DC output range of 50 V to 5000 V, and the resistance measurement resolution can reach 0.1 $M\Omega.$ Since most safety regulations require AC power supply for ground bond

test, the GPT-10000 Series provides 8 Vac (open) and 3 A to 32 Aac current for ground bond test with a resistance measurement resolution of 0.1 m Ω . The entire series provides the continuity grounding test function with a 100 mAdc (fixed) test source and a measurement resolution of 0.01 Ω to detect if the tested equipment is correctly grounded. With these functions, users can perform various safety tests and verifications with high accuracy and reliability.

FLEXIBLE SUPPLEMENTARY TESTING MECHANISM



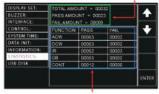
Testing Period Timing

To make tests compliant with the test requirements of relevant safety regulations, the GPT-10000 Series provides a more flexible output sequence setting starting from the start point of the test. Taking the AC/DC withstand voltage test as an example, the initial voltage can be set. Users determine the initial voltage ratio (i.e., the ratio of the rated test voltage), and then the voltage ramp up can also be set to reduce the risk of insulation breakdown or damage to the DUT caused by transient high voltages. After the rated test voltage is reached, the upper/lower limit judgement window, delay judgment and test timer mechanism can be set to assist users to conduct tests smoothly and correctly. The new voltage ramp down time setting allows users to test with a ramp down voltage to

avoid the impact of excessively high rated test voltage to instantaneous discharge on the DUT.

With respect to the insulation resistance test, other than the newly added grounding mode to perform test in accordance with the actual grounding state of the DUT, the setting mechanism of the supplementary upper/lower limit judgement is also added to shorten the test time. The user-definable mode mechanisms include: STOP ON FAIL: The test is terminated as soon as the FAIL setting is met; STOP ON PASS: The test is terminated as long as the PASS setting is met, or TIMER: judgement is conducted when the timer time is reached.

PASS, FAIL Amounts & TOTAL Amounts



PASS & FAIL Amounts Distributions in Each

Statistic

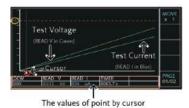
The GPT-10000 Series provides the statistic function, which can record the test functions and judgment results in the temporary storage area (60,000 lots max.). Users can immediately learn the test of each function during the test without using a PC. The distribution of the good products can be analyzed to understand the quality of the batch based on the data. If most



Analysis

of them fall at the critical point that is close to be categorized as defect product, the results can be found in the test process in time so as to improve the manufacturing process and stop the defect products from entering the markets to ensure the reliability of products after leaving the factory.

SWEEP AND TABULAR AUTOMATIC TEST



Sweep Function

The GPT-10000 Series features a unique sweep function, which displays a curve diagram of the test results of the DUT. Test readings are recorded point by point based on the applied test voltage or current and relevant settings (such as initial voltage, ramp up time, test time, or ramp down time). After the test is completed, users can learn the amount of applied energy (voltage or current) at a specific time point and the results of measurement parameters by moving the cursor position so as to help users understand the changes of the measurement parameters (current or resistance) during the test. The function can also be used to determine the

mixed-type production lines. By scanning the barcode of the DUT, GPT-



MANU STEP results indicators

Tabular Automatic Test

critical break down of the DUT. With respect to the automatic test function, each automatic test has up to 10 manual test items and all related settings and result judgement are presented in a table, so that users can easily obtain the results of all test items at a time. Other than that, if there are multiple automatic test connection requirements, uses only need to select CON in the last item of the table to automatically connect the automatic measurement of the next position (such as AUTO-012 ~ AUTO-013)

F. BARCODE FUNCTION



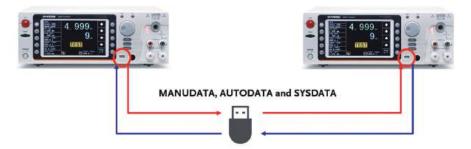
Barcode Setting

GPT-10000 Series supports the connection mechanism of the barcode machine. Users can manage the test conditions of each DUT through the use and setting of the barcode machine, which is especially suitable for



Barcode Execute

10000 Series can automatically reveal the corresponding test conditions, which can avoid using wrong conditions and causing damage to the DUT.



Setting Data Export / Import

In order to expedite the deployment of the production line and achieve the consistency of test conditions, GPT-10000 Series provides a mechanism that can replicate test conditions. Users only need to set test conditions

for one unit, and all settings can be copied via a USB flash drive. Other than the rapid setting of consistent test conditions, it can also avoid the difference while conducting settings.

Н.

COMPLETE TEST DATA RETRIEVAL INTERFACE

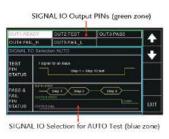


Storage Function

In order to facilitate users to analyze the results of the safety test, GPT-10000 Series provides the USB storage function in addition to its own statistic and analysis functions. When a USB is inserted and the storage function is activated, each time the test button (START) is pressed, the test results of all tests (every manual or automatic test item) are automatically saved to the USB in the form of a text file (txt) for follow-up analysis. When

there is no USB flash drive available, users can turn on the internal memory storage function (up to 30,000 lots) to store the results of each test in theinternal memory first, and then transfer them to an external device via a USB flash drive when available. Besides, the entire series is equipped with RS-232C and USB device (GPIB or LAN is optional) for easy retrieval of test data and results by connecting a PC.

USER DEFINED SIGNAL I/O



Self-defined Signal I/O

For interface connections, the GPT-10000 Series offers external control or a variety of remotely connected ports such as a signal I/O port that can be used to connect an external controller or PLC. The signal I/O's output

signal pins can be self-defined so as to collocate with various PLC control requirements.

PANEL INTRODUCTION



SELECTION GUIDE

Function Model	Output Capacity	AC	DC	IR	GB	Continuity	Rear Output
GPT-15012	12kVdc		✓	1			✓
GPT-15001	500VA	✓				✓	✓
GPT-15002	500VA	✓	✓			✓	✓
GPT-15003	500VA	✓	✓	1		✓	✓
GPT-15004	500VA	✓	✓	1	✓	✓	✓
GPT-12001	200VA	✓				✓	✓
GPT-12002	200VA	✓	✓			✓	✓
GPT-12003	200VA	✓	✓	✓		✓	✓
GPT-12004	200VA	✓	1	1	1	✓	✓

Note: GPT-15000 Series ACW short current > 200 mA

7. USB Host

APPLICATIONS

14. GPIB or LAN (optional)

Safety Testing of Electrical Product in Manufacturing
 Power Cord
 Home Appliances
 Information Technology Equipment
 Medical Equipment

Medical Equipment Household and Similar Electrical Appliances

Luminaires

Audio, Video and Similar Electronic Apparatus

- Quality Assurance Verification
- Safety Standard Compliance Pre-qualification in R&D

MININE THE CHIENS			
MODEL	GPT-15012	GPT-15000 Series	GPT-12000 Series
AC WITHSTANDING			
Output-Voltage Range		0.050 kV to 5.000 kV	0.050 kV-5.000 kV
Output-Voltage Resolution		7 V ±(7 % of setting+ 5 VJ [no load]	7V
Output-Voltage Accuracy Maximum Rated Load		\$00VA 5 kV/ 700 mAJ	±(7 % of setting+ 5 VJ [no load] 200 VA (5 kV/ 40 mAJ
Maximum Rated Current		700 mA (0.5 kV <v:'as kv);<="" th=""><th>40 mA (0.5 kV<v:'as kv);<="" th=""></v:'as></th></v:'as>	40 mA (0.5 kV <v:'as kv);<="" th=""></v:'as>
		70 mA (0.05 kV:e;V 0.5 kV)	70 mA (0.05 kV V 0.5 kV)
Output-Voltage Waveform	-	Sine wave	Sine wave
Output-Voltage Frequency		50 Hz / 60 Hz selectable	50 Hz / 60 Hz selectable
Voltage Regulation Voltmeter Accuracy		±(7 % + 5 VJ [maximum rated load - no load]	±(7 % + 5 VJ [maximum rated load - no load]
Current Measurement Range		±(7 % of reading+ 5 VJ	±(7 % of reading+ 5 VJ 7 µA to 40.00 mA
Current Best Resolution		7 μA to 700.0 mA 7 μΑ/70μΑ/700μΑ	7 μΑ 10 40.00 MA 7 μΑ/70μΑ
Current Measurement Accuracy		±(7 .5% ofreading + 30 μA)	±(7 .5% ofreading + 30 μA)
Current Offset		60 μA Maximum	60 μA Maximum
Window Comparator Method		Yes	Yes
ARC Detect RAMP UP (Rise Time]		Yes	Yes
RAMP DOWN (Fall Time)		07 sto999.9s 0.0 s to 999.9 s	0.7 sto 999.9 s 0.0 s to 999.9 s
TIMER [Test Time)*		OFF, 0.3 s to 999.9 s	OFF, 0.3 s to 999.9 s
WAIT TIME		0.0 s to 999.9 s	0.0 s to 999.9 s
GND		ON/OFF	ON/OFF
DC WITHSTANDING			
Output-Voltage Range	0.050 kV to 12.00 kV	0.050 kV to 6.000 kV	0.050 kV to 6.000 kV
Output-Voltage Resolution	7V	7V	7V
Output-Voltage Accuracy Maximum Rated Load	±(7% of setting+ 5 VJ [no load] 720 W (72 kV/70 mA)	±(7 % of setting+ 5 VJ [no load] 700W (5 kV /20mA)	±(7 % of setting+ 5 V) [no load] SOW (5 kV/ 70 mA)
Maximum Rated Current	720 W (72 KV) 70 HA) 70 mA (0.5 kV <v:'a72 kv);<="" th=""><th>20 mA (0.5 kV<v 6="" kv);<="" th=""><th>70mA (0.5 kV<v kv);<="" s="" th=""></v></th></v></th></v:'a72>	20 mA (0.5 kV <v 6="" kv);<="" th=""><th>70mA (0.5 kV<v kv);<="" s="" th=""></v></th></v>	70mA (0.5 kV <v kv);<="" s="" th=""></v>
	2mA (0.os kv:e:v:e:o.s kV)	2 mA (0.os kv:e:v:e:o.s kV)	2mA (0.05 kv:e:v:e: 0.SkVJ
Voltage Regulation	±(7% + 5 VJ [maximum rated load - no load]	±(7 % + 5 VJ [maximum rated load - no load]	±(7 % + 5 VJ [maximum rated load - no load]
Voltmeter Accuracy	±(7% ofreading + 5 VJ	±(7 % of reading+ 5 VJ	±(7 % of reading+ 5 VJ
Current Measurement Range Current Best Resolution	7 μA to 70.00 mA	7 µA to 20.00 mA	7 µA to 70.00 mA
Current Measurement Accuracy	0.7 μA/7 μA/70μA ±(I.5% ofreading + 3 μA) when I Reading ⊲ mA;	07 μA/7 μA/70μA ±(7.5% of reading+3 μA) when I Reading ⊲ mA;	07 μA/7 μA/70μA ±(7.5% ofreading + 3 μA) when I Reading< 7 mA;
•	±(1.5% of reading + 3 μA) when I Reading <7 mA; ±(1.5% of reading + 30 μA) when I Reading "'7 mA	±(7.5% of reading + 3 µA) when T Reading <7 mA; ±(7.5% of reading + 30 µA) when T Reading '''7 mA	\pm (7.5% of reading + 3 μ A) when I Reading < 7 mA; \pm (7.5% of reading + 30 μ A) when I Reading "'7 mA
Current Offset	5 µA Maximum	5 µA Maximum	5 µA Maximum
Window Comparator Method	Yes	Yes	Yes
ARC Detect RAMP UP (Rise Time)	Yes	Yes	Yes
RAMP DOWN (Fall Time)	0.7 s to 999.9 s	07 sto999.9s	07 sto999.9s
TIMER [Test Time)*	0.0 s to 999.9 s OFF, 0.3 s to 999.9 s	0.0 s to 999.9 s OFF, 0.3 s to 999.9 s	0.0 s to 999.9 s OFF, 0.3 s to 999.9 s
WAIT TIME	0.0 s to 999.9 s	0.0 s to 999.9 s	0.0 s to 999.9 s
GND	ON/OFF	ON/OFF	ON/OFF
INSULATION RESISTANCE		(Firmware version: V.1.06 or later)	(Firmware version: V.1.12 or later)
Output Voltage	50 V to 5000V de	50 V to 5000 V de	50 V to 5000 V de
Output-Voltage Resolution	SOY	SOY	SOY
Output-Voltage Accuracy Resistance Measurement	±(7% of setting+ 5 VJ [no load]	±(7%ofsetting+ SV) [no load]	±(7 % of setting+ 5 V) [no load]
Test Volta2e Disolav Ransre	Measurement Range / Accuracy	Measurement Rane:e / Accuracy	Measurement Rane:e / Accuracv
sov;a;v;,;100v 0001 Mil to 1000 Gil	0.7 Mn to 7 Mil:±(5% of reading+ 3 count);	0.7 Mn to 7 Mil:±(5% ofreading + 3 count);	0.7 Mn to 7 Mil:±(5% of reading+ 3 count);
100	11 Mn to 50 Mil:±(5% of reading+ 1 count);	11 Mn to 50 Mil:±(5% ofreading + 1 count);	11 Mn to 50 Mil:±(5% ofreading + 1 count);
1SOv;a;v;;;mv 0001 Mh to 2000 Gil	50.7 Mn to 2 en:±(7 0% ofreading + 7 count)	50. 7 Mn to 2 en:±(70% ofreading + 7 count)	50.7 Mn to 2 en:±(70% of reading+ 7 count)
soov;a;v;;;12oov 0001 Mil to 5000 Gil	0.7 Mn to 7 Mil:±(5% of reading+ 3 count);	07 Mn to 7 Mil:±(5% ofreading + 3 count);	07 Mn to 7 Mil:±(5% of reading+ 3 count);
	11 Mn to 500 Mil:±(5% ofreading + 1 count); 500.7 Mn to 9.999 en:±(70% ofreading + 7 count);	11 Mn to 500 Mil:±(5% ofreading + 1 count); 500.7 Mn to 9.999 en:±(7 0% ofreading + 7 count);	11 Mn to 500 Mil:±(5% of reading+ 1 count); 500.7 Mn to 9.999 en:±(70% of reading+ 7 count);
	10 e n to 50 en:±(20% of reading + 1 count)	10 e n to 50 en:±(20% of reading + 1 count)	10 e n to 50 en:±(20% of reading+ 1 count)
mov;;;v;;;sooov 0.001 Miltoso.oocn		01 Mn to 1 Mil:±(5% ofreading + 3 count);	01 Mn to 1 Mll:±(5% of reading+ 3 count);
	I.7 Mn to 500 Mil:±(5% ofreading + 7 count);	77 Mn to 500 Mil:±(5% ofreading + 7 count);	77 Mn to 500 Mil:±(5% of reading+ 7 count);
	500.1 Mn to 9.999 en:±(10% ofreading + 1 count);	500.1 Mn to 9.999 ell:±(10% ofreading + 1 count);	500.1 Mn to 9.999 ell:±(10% of reading+ 1 count);
Veltage Demulation	70 e n to 50 en:±(75% ofreading + 7 count)	70 e n to 50 en:±(7 5% of reading+ 7 count) ±(7 % + 5 VJ [maximum rated load – no load]	70 e n to 50 en:±(75% of reading+ 7 count)
Voltage Regulation Voltmeter Accuracy	±(7% + 5 V) [maximum rated load – no load] ±(7% of reading+ 5 V)	±(7 % + 5 V) [maximum rated load - no load] ±(7 % of reading+ 5 V)	±(7 % + 5 VJ [maximum rated load – no load] ±(7 % of reading+ 5 VJ
Short-Circuit Current	10 mA max.	70 mA max.	70 mA max.
Output Impedance	2 kn	2 kn	2 kll
Window Comparator Method	Yes	Yes	Yes
DAMP UP (D) \		01 sto999.9s	01 sto999.9s
RAMP UP (Rise Time)	0.1 s to 999.9 s		
RAMP DOWN (Fall Time)	0.0 s to 999.9 s	0.0 s to 999.9 s	0.0 s to 999.9 s
RAMP DOWN (Fall Time) TIMER [Test Time)* WAIT TIME e N D	0.0 s to 999.9 s 0.3 s to 999.9 s	0.0 s to 999.9 s 0.3 s to 999.9 s	0.0 s to 999.9 s 0.3 s to 999.9 s
RAMP DOWN (Fall Time) TIMER (Test Time)* WAIT TIME e N D GROUND BOND	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s ON/OFF	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s ON/OFF
RAMP DOWN (Fall Time) TIMER (Test Time)* WAIT TIME e N D GROUND BOND Output-Current	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s ON/OFF	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s ON/OFF
RAMP DOWN (Fall Time) TIMER (Test Time)* WAIT TIME e N D GROUND BOND Output-Current Output-Current Resolution	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s ON/OFF	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s ON/OFF
RAMP DOWN (Fall Time) TIMER (Test Time)* WAIT TIME e N D GROUND BOND Output-Current	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0N/OFF 03.00 A to 32.00 A ac 0.07A 3 A I az8 A:±(1% of reading+ 0.2 A);	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0N/OFF 03.00 A to 32.00 A ac 0.07A 3 A ka:;8 A:±(1% ofreading + 0.2 A);
RAMP DOWN (Fall Time) TIMER (Test Time)* WAIT TIME e N D GROUND BOND Output-Current Output-Current Resolution	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0N/OFF 03.00 A to 32.00 A ac 0.07A 3 A ag8 A:±(1% of reading+ 0.2 A); 8 A< a;32 A:±(7% ofreading+ 0.05 A)	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0N/OFF 03.00 A to 32.00 A ac 0.07A 3 A La:;8 A:±(1% ofreading + 0.2 A); 8 A <i:'a32 +="" 0.05="" a)<="" a:±(7%="" of="" reading="" td=""></i:'a32>
RAMP DOWN (Fall Time) TIMER (Test Time)* WAIT TIME e N D GROUND BOND Output-Current Output-Current Resolution Output-Current Accuracy Test-Voltage Test-Voltage Test-Voltage Frequency	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0N/OFF 03.00 A to 32.00 A ac 0.07A 3 A I az8 A:±(1% of reading+ 0.2 A);	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0N/OFF 03.00 A to 32.00 A ac 0.07A 3 A ka;8 A:±(1% ofreading + 0.2 A);
RAMP DOWN (Fall Time) TIMER (Test Time)* WAIT TIME eND GROUND BOND Output-Current Output-Current Resolution Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Range	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s ON/OFF 03.00 A to 32.00 A ac 0.07A 3 A I ag A:±(1% of reading+ 0.2 A); 8 A <i +="" 0.05="" a)<br="" a:±(7%="" arg.="" ofreading="">8 Vac max (open circuit)</i>	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0N/OFF 03.00 A to 32.00 A ac 0.07A 3 Al:a;8 A:±(1% ofreading + 0.2 A); 8 Acl:'a32 A:±(7% of reading+ 0.05 A) 8 Vac max (open circuit)
RAMP DOWN (Fall Time) TIMER (Test Time)* WAIT TIME eND GROUND BOND Output-Current Resolution Output-Current Accuracy Test-Voltage Test-Voltage Test-Voltage Ohmmeter Measurement Range Ohmmeter Measurement Resolution	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0N/OFF 03.00 A to 32.00 A ac 0.07A 3 A I agA A:±(1% of reading+ 0.2 A); 8 A <i (open="" +="" 0.05="" 01="" 50="" 60="" 650="" 7="" 8="" a)="" a:±(7%="" ag3="" circuit)="" hz="" max="" mil="" mn<="" ofreading="" selectable="" td="" to="" vac=""><td>0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0N/OFF 03.00 A to 32.00 A ac 0.07A 3 A La:,8 A:±(1% ofreading + 0.2 A); 8 A<i:'a32 (open="" 0.05="" 01="" 50="" 60="" 650="" 7="" 8="" a)="" a:±(7%="" circuit)="" hz="" max="" mil="" mn<="" of="" reading+="" selectable="" td="" to="" vac=""></i:'a32></td></i>	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0N/OFF 03.00 A to 32.00 A ac 0.07A 3 A La:,8 A:±(1% ofreading + 0.2 A); 8 A <i:'a32 (open="" 0.05="" 01="" 50="" 60="" 650="" 7="" 8="" a)="" a:±(7%="" circuit)="" hz="" max="" mil="" mn<="" of="" reading+="" selectable="" td="" to="" vac=""></i:'a32>
RAMP DOWN (Fall Time) TIMER (Test Time)* WAIT TIME e N D GROUND BOND Output-Current Output-Current Resolution Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Range Ohmmeter Measurement Resolution Ohmmeter Measurement Resolution	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0.0/OFF 03.00 A to 32.00 A ac 0.07A 3 A I as A:±(1% of reading+ 0.2 A); 8 A <i %="" (open="" +="" 0.05="" 01="" 2="" 50="" 60="" 650="" 7="" 8="" a)="" a:±(7%="" a;32="" circuit)="" hz="" max="" mil="" mil)<="" mn="" of="" ofreading="" reading+="" selectable="" td="" to="" vac="" ±(7=""><td>0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0.0/OFF 03.00 A to 32.00 A ac 0.07A 3 A!a;3 A:±(1% ofreading + 0.2 A); 8 AA:!a32 A:±(7% of reading+ 0.05 A) 8 Vac max (open circuit) 50 Hz/60 Hz selectable 7 mil to 650 mil 0.1 mn ±(7 % of reading+ 2 mil)</td></i>	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0.0/OFF 03.00 A to 32.00 A ac 0.07A 3 A!a;3 A:±(1% ofreading + 0.2 A); 8 AA:!a32 A:±(7% of reading+ 0.05 A) 8 Vac max (open circuit) 50 Hz/60 Hz selectable 7 mil to 650 mil 0.1 mn ±(7 % of reading+ 2 mil)
RAMP DOWN (Fall Time) TIMER (Test Time)* WAIT TIME e N D GROUND BOND Output-Current Output-Current Resolution Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Range Ohmmeter Measurement Resolution Ohmmeter Measurement Accuracy Window Comparator Method	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0N/OFF 03.00 A to 32.00 A ac 0.07A 3 A I zz8 A:±(1% of reading+ 0.2 A); 8 A <i %="" (open="" +="" 0.05="" 01="" 2="" 50="" 60="" 650="" 7="" 8="" a)="" a:±(7%="" circuit)="" hz="" max="" mil="" mil)="" mn="" of="" reading="" reading+="" selectable="" td="" to="" vac="" yes<="" zz32="" ±(7=""><td>0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0.0 s to 999.9 s 0.07A 3.0.0 A to 32.00 A ac 0.07A 3.A.La:;8 A:±(1% ofreading + 0.2 A); 8.A.L.'a32 A:±(7% of reading+ 0.05 A) 8.Vac max (open circuit) 5.0 Hz/60 Hz selectable 7 mil to 650 mil 0.1 mn ±(7 % of reading+ 2 mil) Yes</td></i>	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0.0 s to 999.9 s 0.07A 3.0.0 A to 32.00 A ac 0.07A 3.A.La:;8 A:±(1% ofreading + 0.2 A); 8.A.L.'a32 A:±(7% of reading+ 0.05 A) 8.Vac max (open circuit) 5.0 Hz/60 Hz selectable 7 mil to 650 mil 0.1 mn ±(7 % of reading+ 2 mil) Yes
RAMP DOWN (Fall Time) TIMER (Test Time)* WAIT TIME e N D GROUND BOND Output-Current Output-Current Resolution Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Range Ohmmeter Measurement Resolution Ohmmeter Measurement Resolution	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0N/OFF 03.00 A to 32.00 A ac 0.07A 3 A I a;3 A:±(1% of reading+ 0.2 A); 8 A <i %="" (open="" +="" 0.05="" 0.3="" 01="" 2="" 50="" 60="" 650="" 7="" 8="" 999.9="" a)="" a:±(7%="" a;32="" circuit)="" hz="" max="" mil="" mil)="" mn="" of="" ofreading="" reading+="" s="" s<="" selectable="" td="" to="" vac="" yes="" ±(7=""><td>0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0.0/OFF 03.00 A to 32.00 A ac 0.07A 3 Al:a;8 A:±(1% ofreading + 0.2 A); 8 A<!--:'a32 A:±(7% of reading+ 0.05 A) 8 Vac max (open circuit) 50 Hz/60 Hz selectable 7 mil to 550 mil 01 mn ±(7 % of reading+ 2 mil) Yes 0.3 s to 999.9 s</td--></td></i>	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0.0/OFF 03.00 A to 32.00 A ac 0.07A 3 Al:a;8 A:±(1% ofreading + 0.2 A); 8 A :'a32 A:±(7% of reading+ 0.05 A) 8 Vac max (open circuit) 50 Hz/60 Hz selectable 7 mil to 550 mil 01 mn ±(7 % of reading+ 2 mil) Yes 0.3 s to 999.9 s</td
RAMP DOWN (Fall Time) TIMER [Test Time)* WAIT TIME eND GROUND BOND Output-Current Output-Current Resolution Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Range Ohmmeter Measurement Resolution Ohmmeter Measurement Accuracy Window Comparator Method TIMER [Test Time)*	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0.0/OFF 03.00 A to 32.00 A ac 0.07A 3 A I	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0.0/OFF 03.00 A to 32.00 A ac 0.07A 3 A la:,8 A:±(1% ofreading + 0.2 A); 8 A <l:'a32 %="" (open="" 0.05="" 0.3="" 01="" 2="" 50="" 60="" 650="" 7="" 8="" 999.9="" a)="" a:±(7%="" circuit)="" four="" hz="" max="" mil="" mil)="" mn="" of="" reading+="" s="" selectable="" td="" terminal<="" to="" vac="" yes="" ±(7=""></l:'a32>
RAMP DOWN (Fall Time) TIMER [Test Time)* WAIT TIME e N D GROUND BOND Output-Current Output-Current Resolution Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Range Ohmmeter Measurement Resolution Ohmmeter Measurement Accuracy Window Comparator Method TIMER [Test Time)* Test Method GND	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0N/OFF 03.00 A to 32.00 A ac 0.07A 3 A I a;3 A:±(1% of reading+ 0.2 A); 8 A <i %="" (open="" +="" 0.05="" 0.3="" 01="" 2="" 50="" 60="" 650="" 7="" 8="" 999.9="" a)="" a:±(7%="" a;32="" circuit)="" hz="" max="" mil="" mil)="" mn="" of="" ofreading="" reading+="" s="" s<="" selectable="" td="" to="" vac="" yes="" ±(7=""><td>0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0.0/OFF 03.00 A to 32.00 A ac 0.07A 3 Al:a;8 A:±(1% ofreading + 0.2 A); 8 A<!--:'a32 A:±(7% of reading+ 0.05 A) 8 Vac max (open circuit) 50 Hz/60 Hz selectable 7 mil to 550 mil 01 mn ±(7 % of reading+ 2 mil) Yes 0.3 s to 999.9 s</td--></td></i>	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0.0/OFF 03.00 A to 32.00 A ac 0.07A 3 Al:a;8 A:±(1% ofreading + 0.2 A); 8 A :'a32 A:±(7% of reading+ 0.05 A) 8 Vac max (open circuit) 50 Hz/60 Hz selectable 7 mil to 550 mil 01 mn ±(7 % of reading+ 2 mil) Yes 0.3 s to 999.9 s</td
RAMP DOWN (Fall Time) TIMER [Test Time)* WAIT TIME e N D GROUND BOND Output-Current Output-Current Resolution Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Range Ohmmeter Measurement Resolution Ohmmeter Measurement Accuracy Window Comparator Method TIMER [Test Time)* Test Method	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0N/OFF 03.00 A to 32.00 A ac 0.07A 3 A I za A:±(1% of reading+ 0.2 A); 8 A Cl za A:±(7% of reading + 0.05 A) 8 Vac max (open circuit) 50 Hz/60 Hz selectable 7 mil to 650 mil 01 mn ±(7 % of reading+ 2 mil) Yes 0.3 s to 999.9 s Four Terminal ON/OFF	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0.0/OFF 03.00 A to 32.00 A ac 0.07A 3 A la:,8 A:±(1% ofreading + 0.2 A); 8 A <l:'a32 %="" (open="" 0.05="" 0.3="" 01="" 2="" 50="" 60="" 650="" 7="" 8="" 999.9="" a)="" a:±(7%="" circuit)="" four="" hz="" max="" mil="" mil)="" mn="" of="" reading+="" s="" selectable="" terminal<="" th="" to="" vac="" yes="" ±(7=""></l:'a32>
RAMP DOWN (Fall Time) TIMER [Test Time)* WAIT TIME e N D GROUND BOND Output-Current Output-Current Resolution Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Range Ohmmeter Measurement Accuracy Window Comparator Method TIMER [Test Time)* Test Method GND CONTINUITY TEST Output-Current Ohmmeter Measurement Range	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0.0/OFF 03.00 A to 32.00 A ac 0.07A 3 A I	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0.0 s to 999.9 s 0.07A 3 A l:a; 8 A:±(1% ofreading + 0.2 A); 8 A<1: a32 A:±(7% of reading+ 0.05 A) 8 Vac max (open circuit) 50 Hz/60 Hz selectable 7 mil to 650 mil 0.1 mn ±(7 % of reading+ 2 mil) Yes 0.3 s to 999.9 s Four Terminal 0.0N/OFF
RAMP DOWN (Fall Time) TIMER (Test Time)* WAIT TIME e N D GROUND BOND Output-Current Output-Current Resolution Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Range Ohmmeter Measurement Accuracy Window Comparator Method TIMER (Test Time)* Test Method GND CONTINUITY TEST Output-Current Ohmmeter Measurement Range Ohmmeter Measurement Accuracy	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0N/OFF 03.00 A to 32.00 A ac 0.07A 3 A I zaß A:±(1% of reading+ 0.2 A); 8 A <i %="" (fixed)="" (open="" +="" 0.05="" 0.10="" 0.3="" 001="" 01="" 0n="" 2="" 50="" 60="" 650="" 7="" 70.00="" 700="" 8="" 999.9="" a)="" a:±(7%="" circuit)="" de="" four="" hz="" ma="" max="" mil="" mil)="" mn="" n="" n<="" of="" off="" reading="" reading+="" s="" selectable="" td="" terminal="" to="" vac="" yes="" zaß="" ±7=""><td>0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0.N/OFF 03.00 A to 32.00 A ac 0.07A 3 Al:a;8 A:±(1% ofreading + 0.2 A); 8 Acl:'a32 A:±(7% of reading+ 0.05 A) 8 Vac (pac (pac) circuit) 5 U Hz/60 Hz selectable 7 mil to 650 mil 0.1 mn 4t/7 % of reading+ 2 mil) Yes 0.3 s to 999.9 s Four Terminal 0.N/OFF 700 mA de (fixed) 0.10 to 70.0011 001 n</td></i>	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0.N/OFF 03.00 A to 32.00 A ac 0.07A 3 Al:a;8 A:±(1% ofreading + 0.2 A); 8 Acl:'a32 A:±(7% of reading+ 0.05 A) 8 Vac (pac (pac) circuit) 5 U Hz/60 Hz selectable 7 mil to 650 mil 0.1 mn 4t/7 % of reading+ 2 mil) Yes 0.3 s to 999.9 s Four Terminal 0.N/OFF 700 mA de (fixed) 0.10 to 70.0011 001 n
RAMP DOWN (Fall Time) TIMER (Test Time)* WAIT TIME eND GROUND BOND Output-Current Output-Current Resolution Output-Current Accuracy Test-Voltage Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Range Ohmmeter Measurement Resolution Ohmmeter Measurement Accuracy Window Comparator Method TIMER (Test Time)* Test Method GND CONTINUITY TEST Output-Current Ohmmeter Measurement Range Ohmmeter Measurement Range Ohmmeter Measurement Range	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0.N/OFF 03.00 A to 32.00 A ac 0.07A 3 A I ag8 A:±(1% of reading+ 0.2 A); 8 A<1 a;32 A:±(7% of reading + 0.05 A) 8 Vac max (open circuit) 50 Hz/60 Hz selectable 7 mil to 650 mil 01 mn ±(7 % of reading+ 2 mil) Yes 0.3 s to 999.9 s Four Terminal ON/OFF 700 mA de (fixed) 0.10 n to 70.00 n 001 n ±(10% of reading+ 2 II)	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0.N/OFF 03.00 A to 32.00 A ac 0.07A 3 A l:a;8 A:±(1% ofreading + 0.2 A); 8 A<1:'a32 A:±(7% of reading+ 0.05 A) 8 Vac max (open circuit) 50 Hz/60 Hz selectable 7 mil to 650 mil 01 mn ±(7 % of reading+ 2 mil) Yes 0.3 s to 999.9 s Four Terminal ON/OFF 700 mA de (fixed) 0.10llto 70.0011 001 n ±(10% ofreading + 2 ll)
RAMP DOWN (Fall Time) TIMER (Test Time)* WAIT TIME e N D GROUND BOND Output-Current Output-Current Resolution Output-Current Accuracy Test-Voltage Test-Voltage Frequency Ohmmeter Measurement Range Ohmmeter Measurement Accuracy Window Comparator Method TIMER (Test Time)* Test Method GND CONTINUITY TEST Output-Current Ohmmeter Measurement Range Ohmmeter Measurement Accuracy	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0N/OFF 03.00 A to 32.00 A ac 0.07A 3 A I zaß A:±(1% of reading+ 0.2 A); 8 A <i %="" (fixed)="" (open="" +="" 0.05="" 0.10="" 0.3="" 001="" 01="" 0n="" 2="" 50="" 60="" 650="" 7="" 70.00="" 700="" 8="" 999.9="" a)="" a:±(7%="" circuit)="" de="" four="" hz="" ma="" max="" mil="" mil)="" mn="" n="" n<="" of="" off="" reading="" reading+="" s="" selectable="" td="" terminal="" to="" vac="" yes="" zaß="" ±7=""><td>0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0.N/OFF 03.00 A to 32.00 A ac 0.07A 3 Al:a;;8 A:±(1% ofreading + 0.2 A); 8 Acl:'a32 A:±(7% of reading+ 0.05 A) 50 Hz/60 Hz selectable 7 mil to 650 mil 0.1 mn ±(7 % of reading+ 2 mil) Yes 0.3 s to 999.9 s Four Terminal 0.N/OFF 700 mA de (fixed) 0.10 to 70.0011 001 n</td></i>	0.0 s to 999.9 s 0.3 s to 999.9 s 0.0 s to 999.9 s 0.N/OFF 03.00 A to 32.00 A ac 0.07A 3 Al:a;;8 A:±(1% ofreading + 0.2 A); 8 Acl:'a32 A:±(7% of reading+ 0.05 A) 50 Hz/60 Hz selectable 7 mil to 650 mil 0.1 mn ±(7 % of reading+ 2 mil) Yes 0.3 s to 999.9 s Four Terminal 0.N/OFF 700 mA de (fixed) 0.10 to 70.0011 001 n

SPECIFICATIONS					
MODEL	GPT-15012	GPT-15000 Series	GPT-12000 Series		
MEMORY					
Single Step Memory Automatic Testing Memory	MANU : 100 blocks AUTO : 100 blocks, Manu per auto : 10	MANU : 100 blocks AUTO : 100 blocks, Manu per auto : 10	MANU: 100 blocks AUTO: 100 blocks, Manu per auto: 10		
INTERFACE					
Standard (Front) Standard (Rear) Option	REMOTE, USB host Rear Output, RS-232C, USB device, Signal I/O, GPIB, LAN	REMOTE, USB host Rear Output, RS-232C, USB device, Signal I/O, GPIB, LAN	REMOTE, USB host Rear Output, RS-232C, USB device, Signal I/O, GPIB, LAN		
DISPLAY					
	7" color LCD	7" color LCD	7" color LCD		
POWER SOURCE					
	AC 100 V to 240 V ± 10%, 50 Hz / 60 Hz; Power consumption : Max. 400 VA	AC 100 V to 240 V \pm 10%, 50 Hz / 60 Hz; Power consumption : Max. 1000 VA	AC 100 V to 240 V ± 10%, 50 Hz / 60 Hz; Power consumption : Max. 400 VA		
DIMENSIONS** & WEIGHT					
	GPT-15012 : 380 mm x 148 mm x 492 mm; Approx. 9.8 kg	GPT-15001/15002/15003 : 380 mm x 148 mm x 492 mm; Approx. 17 kg(max.) GPT-15004 : 380 mm x 148 mm x 546 mm; Approx. 21 kg	GPT-12001/12002/12003 : 380 mm x 148 mm x 436 mm; Approx. 11 kg(max.) GPT-12004 : 380 mm x 148 mm x 454 mm; Approx. 15 kg		

Note: * TIMER Accuracy: +/-(100ppm+20ms) ** Dimensions: W x H x D

Specifications subject to change without notice.

GPT-10000CD3BH

ORDERING INFORMATION

GPT-15012 DC 12 kV DC/IR Electrical Safety Analyzer GPT-15004 AC 500 VA AC/DC/IR/GB Electrical Safety Analyzer GPT-15003 AC 500 VA AC/DC/IR Electrical Safety Analyzer GPT-15002 AC 500 VA AC/DC Electrical Safety Analyzer GPT-15001 AC 500 VA AC Electrical Safety Analyzer GPT-12004 AC 200 VA AC/DC/IR/GB Electrical Safety Analyzer GPT-12003 AC 200 VA AC/DC/IR Electrical Safety Analyzer GPT-12002 AC 200 VA AC/DC Electrical Safety Analyzer GPT-12001 AC 200 VA AC Electrical Safety Analyzer

Power cord x 1, Interlock Key x 1, Remote Terminal, Cable GHT-119 x 1, Test lead GHT-115 x 1 for GPT-15001/15002/15003/12001/12002/12003, Test lead GHT-115 x 1, GTL-215 x 1 for GPT-15004/12004,

Test lead GHT-120 x 1 for GPT-15012

OPTION

GPT-10KG1 GPIB card GPT-10KL1 LAN card

GHT-117/GHT-117(EU) High Voltage Adapter Box

GHT-118/GHT-118(EU) High Voltage/Ground Bond Adapter Box

GHT-113 High Voltage Test Pistol GHT-205 High Voltage Test Probe

GTL-232 RS232C Cable, 9-pin Female to 9-pin, null Modem for Computer

GTL-246 USB Cable, A-B type, approx. 1.2 m

GHT-122 High Voltage / Continuity Test Lead, Approx. 3000 mm GTL-248 GPIB Cable, approx. 2 m

Signal I/O Converted Cable, 15-pin Male to 9-pin Female. Approx. 200 mm GTL-264

GRA-440 Rack Adapter Panel (19', 4U)

ASSESSORIES GUIDE

Model Assessories	GPT-15012	GPT-15000 Series	GPT-12000 Series
GHT-117/ GHT-117(EU)	_	✓	✓
GHT-118/ GHT-118(EU)	_	✓	✓
GHT-113	_	✓	✓
GHT-205	_	✓	✓
GTL-232	✓	✓	✓
GTL-246	✓	✓	✓
GTL-248	✓	✓	✓
GTL-264	✓	✓	✓
GRA-440	✓	✓	✓
GPT-10KG1	✓	✓	✓
GPT-10KL1	✓	✓	✓
GHT-122	_	✓	✓





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